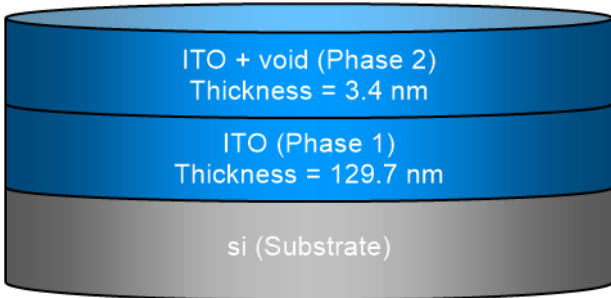


SEA regression report summary

Sample ID
001f 70° 2

Details	
Software and regression log	
Software about	Semilab - Spectroscopic Ellipsometry Analyzer - SEA
Software version	1.7.1
Officially licensed to	MIT
Operator	operator
Date and time of regression	14-07-2021 14:19
Comments	

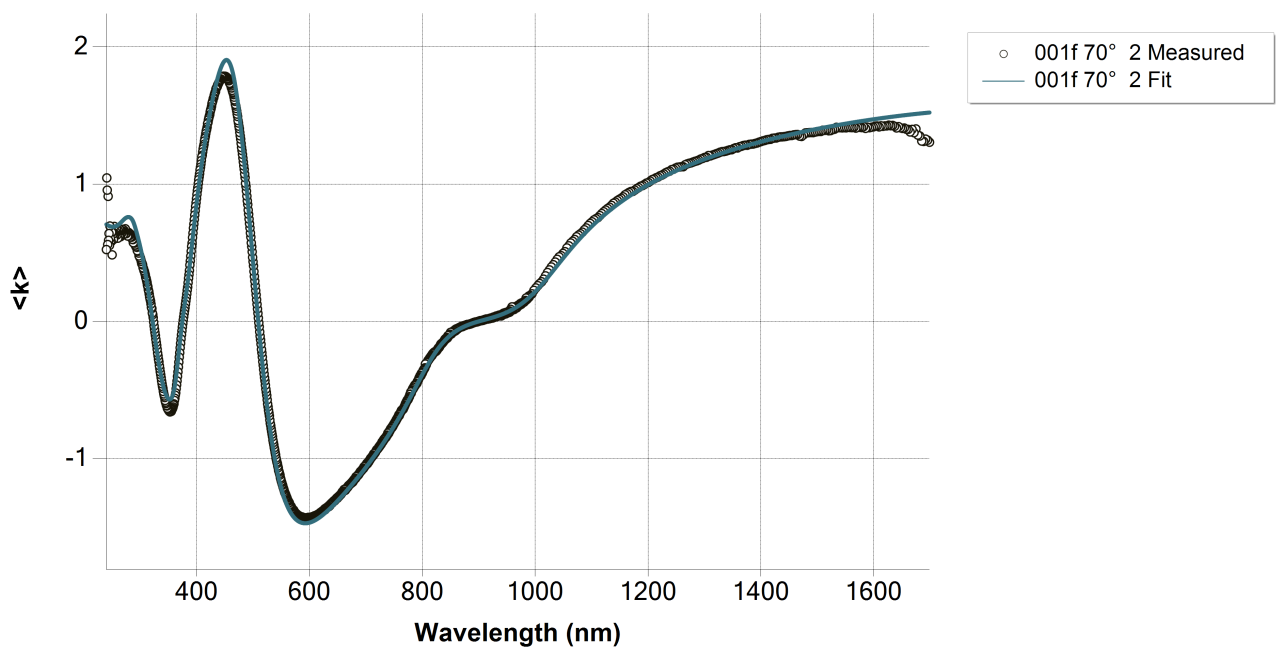
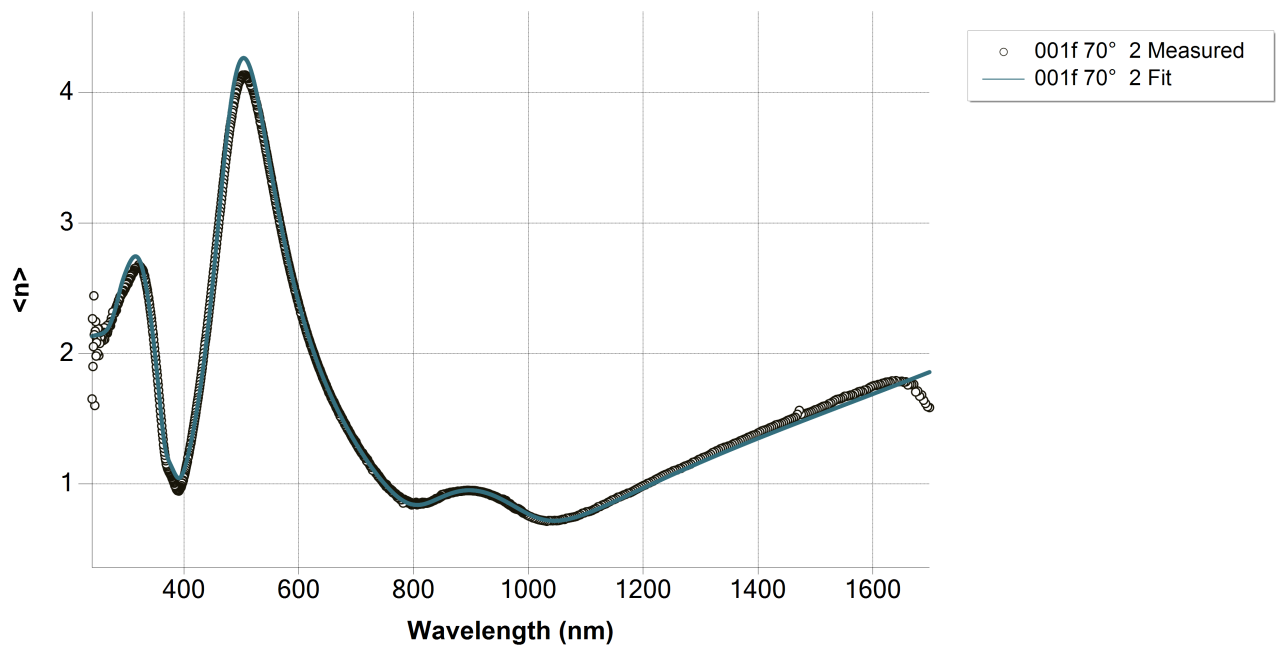
Layer structure	
Overview	
	
Optical model	
Phase 2	ITO + void
Diffusion	
Phase 1	ITO
Dispersion law	Tauc-Lorentz
	Drude

Regression results

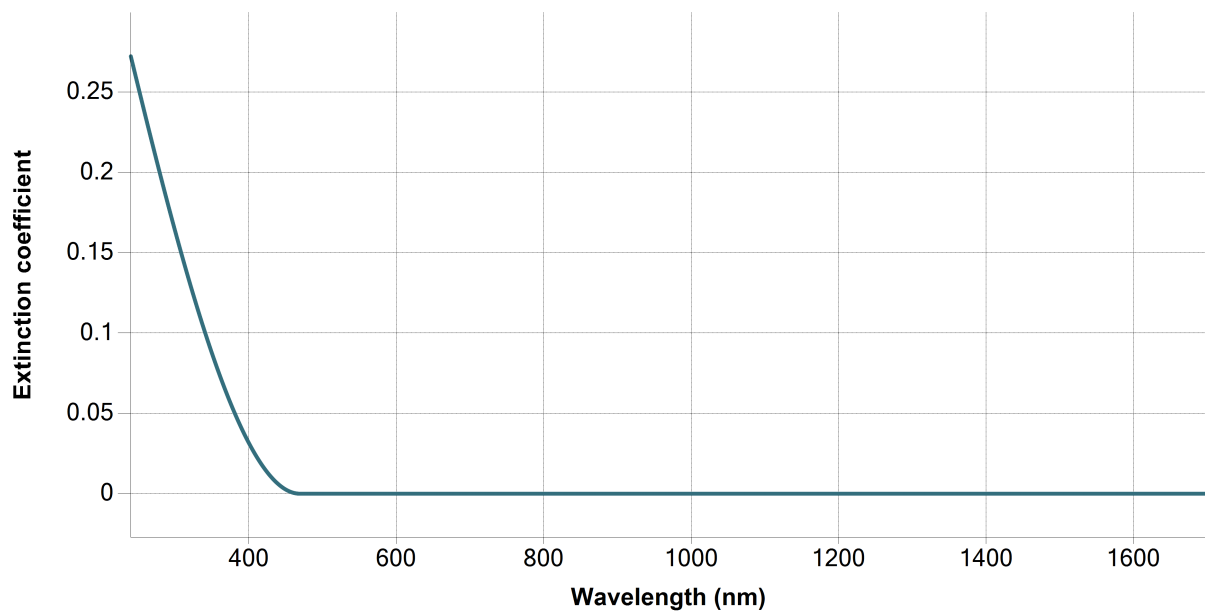
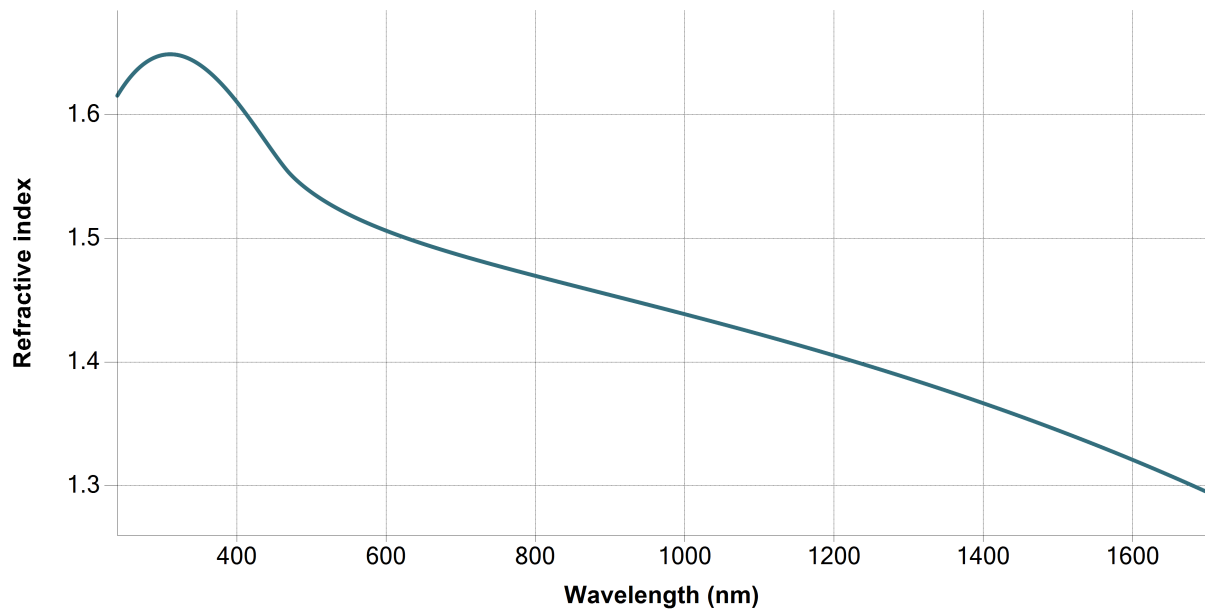
Measurement information				
Measurement file path	C:\Users\emmabat\lito-sil\001f.smdx			
Angle of Incidence	70°			
Regression details				
Regression 1 (EllipsoReflectance)				
Wavelength range	239.84 - 1698.83 nm			
Angle of Incidence	70°			
Fit to	<n>, <k>			
Angular Aperture	0°			
Fit algorithm	LMA			
Results				
Parameters	Value	Fitted	2 σ confidence limit	Unit
Model				
AOI Shift	0			°
Angular Aperture	0			°
Phase 2 (ITO + void)				
Thickness	3.395	X	0.15462	nm
Depolarization coefficient	0.33333			
Concentration 1	0.5			
Concentration 2	0.5			
Phase 1 (ITO)				
Thickness	129.685	X	0.24338	nm
A (eV)	277.28078	X	22.50714	eV
E0 (eV)	9.75634	X	0.18958	eV
C (eV)	40.72861	X	4.14811	eV
Eg (eV)	2.64218	X	0.013976	eV
E_p (eV)	0.9138	X	0.0093745	eV
E_Γ (eV)	0			eV
Eps_inf	0			
Derived parameters	Value			
Phase 2 (ITO + void)				
n @ 632.8 nm	1.499			
k @ 632.8 nm	0			
Phase 1 (ITO)				
n @ 632.8 nm	2.0559			
k @ 632.8 nm	0			
Substrate (si)				
n @ 632.8 nm	3.8811			
k @ 632.8 nm	0.0195			
Drude derived parameters	Value			Unit
Phase 1 (ITO)				
Conductivity (S/m)	∞ ± NaN			S/m
Resistivity (mΩ.cm)	0 ± NaN			mΩ.cm
Resistance (Ω/sq)	0 ± NaN			Ω/sq
N type dopant concentration (at/cm3)	1.514E+20 ± 3.1064E+18			at/cm3

P type dopant concentration (at/cm ³)	2.2407E+20 ± 4.5974E+18	at/cm ³
N type dopant mobility (cm ² /Vs)	∞ ± NaN	cm ² /Vs
P type dopant mobility (cm ² /Vs)	∞ ± NaN	cm ² /Vs
Fit quality		
R ²	0.99682	
RMSE	0.05283	

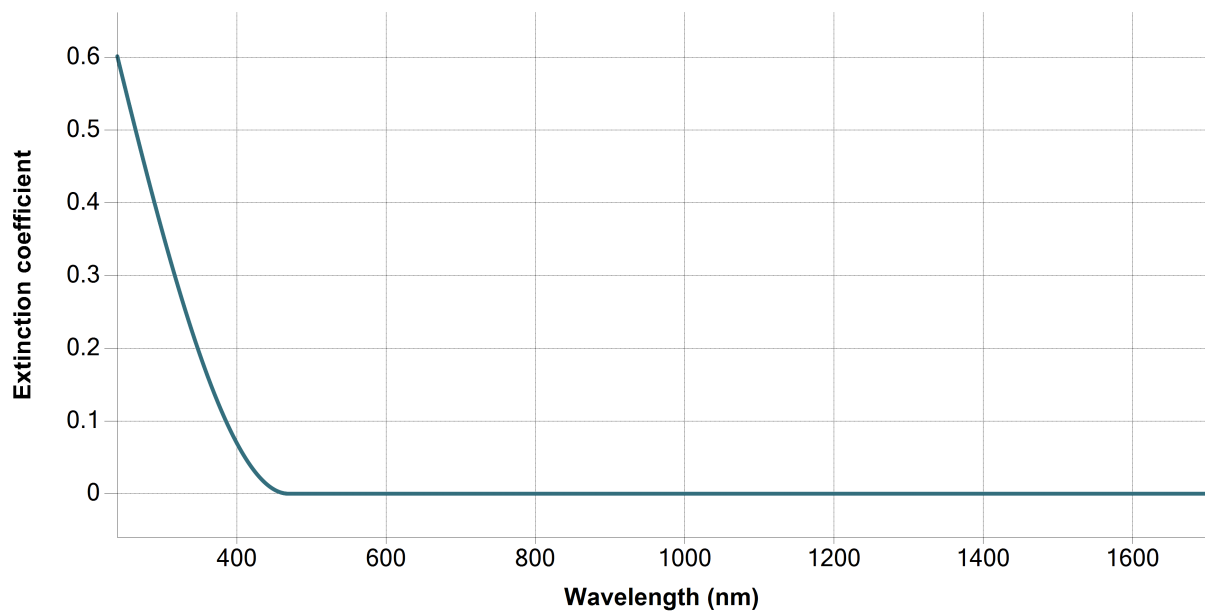
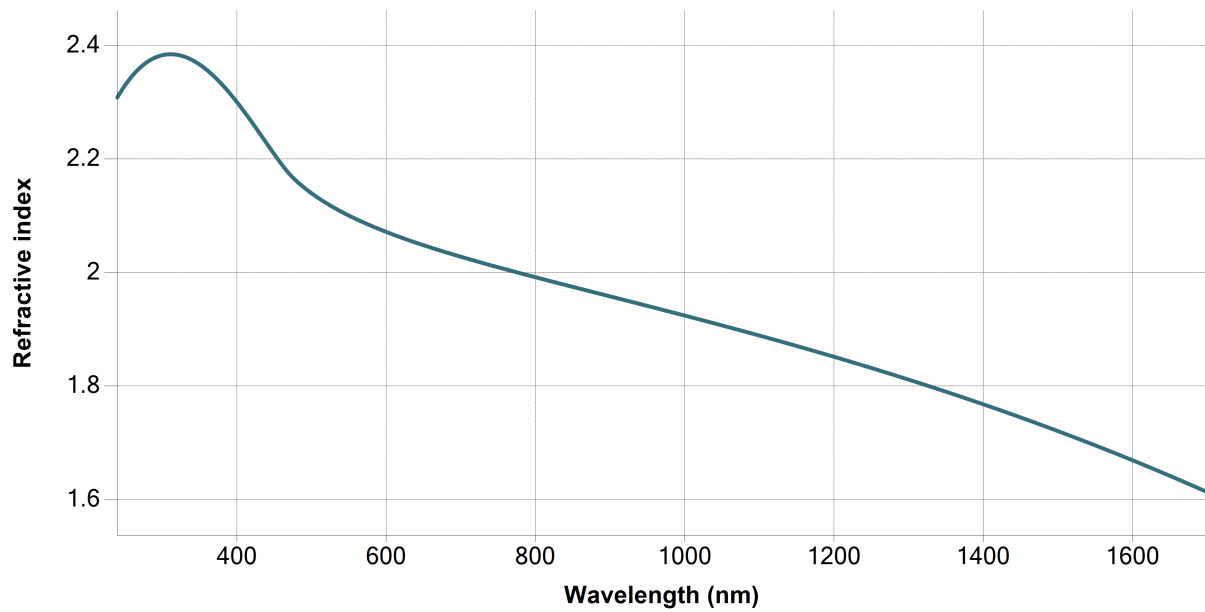
Regression graphs



Phase 2 (ITO + void) - Dispersion graphs



Phase 1 (ITO) - Dispersion graphs



Substrate (si) - Dispersion graphs



Correlation coefficients							
	Ph2 - ITO + void - Thickness	Ph1 - ITO - Thickness	Ph1 - Tauc- Lorentz[1] - A (eV)	Ph1 - Tauc- Lorentz[1] - E0 (eV)	Ph1 - Tauc- Lorentz[1] - C (eV)	Ph1 - Tauc- Lorentz[1] - Eg (eV)	Ph1 - Drude[2] - E_p (eV)
Ph2 - ITO + void - Thickness	1	-0.4223	-0.1071	0.0203	-0.1036	-0.0207	-0.1001
Ph1 - ITO - Thickness		1	0.0008	0.0248	0.0355	0.0089	-0.3017
Ph1 - Tauc- Lorentz[1] - A (eV)			1	0.0989	0.9711	0.8741	0.4562
Ph1 - Tauc- Lorentz[1] - E0 (eV)				1	0.3296	-0.2709	0.3657
Ph1 - Tauc- Lorentz[1] - C (eV)					1	0.7562	0.4977
Ph1 - Tauc- Lorentz[1] - Eg (eV)						1	0.3064
Ph1 - Drude[2] - E_p (eV)							1